



5N50K-TC

Preliminary

Power MOSFET

**5.0A, 500V N-CHANNEL
POWER MOSFET**

■ DESCRIPTION

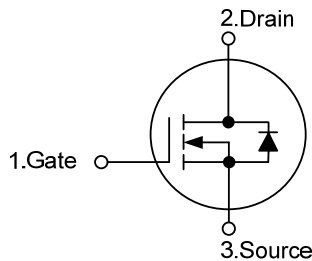
The UTC **5N50K-TC** is an N-channel power MOSFET adopting UTC's advanced technology to provide customers with DMOS, planar stripe technology. This technology is designed to meet the requirements of the minimum on-state resistance and perfect switching performance. It also can withstand high energy pulse in the avalanche and communication mode.

The UTC **5N50K-TC** can be used in applications, such as active power factor correction, high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.

■ FEATURES

- * $R_{DS(ON)} < 1.65\Omega @ V_{GS}=10V, I_D=2.5A$
- * 100% avalanche tested
- * High switching speed

■ SYMBOL

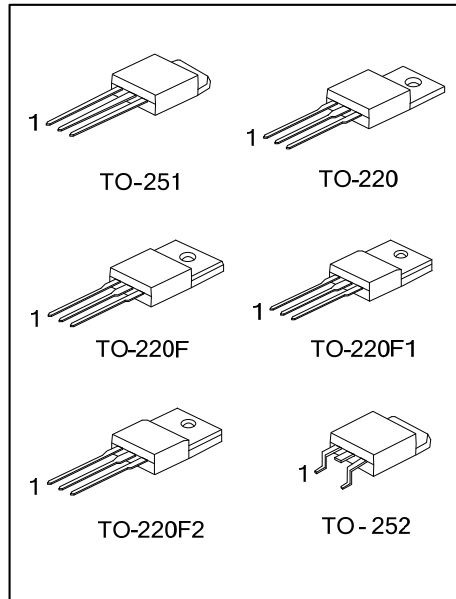


■ ORDERING INFORMATION

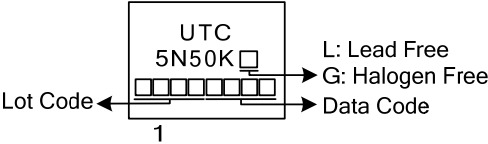
| Ordering Number | | Package | Pin Assignment | | | Packing |
|-----------------|--------------|----------|----------------|---|---|-----------|
| Lead Free | Halogen Free | | 1 | 2 | 3 | |
| 5N50KL-TA3-T | 5N50KG-TA3-T | TO-220 | G | D | S | Tube |
| 5N50KL-TF1-T | 5N50KG-TF1-T | TO-220F1 | G | D | S | Tube |
| 5N50KL-TF3-T | 5N50KG-TF3-T | TO-220F2 | G | D | S | Tube |
| 5N50KL-TF3-T | 5N50KG-TF3-T | TO-220F | G | D | S | Tube |
| 5N50KL-TM3-T | 5N50KG-TM3-T | TO-251 | G | D | S | Tube |
| 5N50KL-TN3-R | 5N50KG-TN3-R | TO-252 | G | D | S | Tape Reel |

Note: Pin Assignment: G: Gate D: Drain S: Source

| | |
|--|--|
| <p>6N60L-TA3-T</p> <p>(1)Packing Type</p> <p>(2)Package Type</p> <p>(3)Green Package</p> | <p>(1) T: Tube, R: Tape Reel</p> <p>(2) TA3: TO-220, TF3: TO-220F, TF1: TO-220F1, TF2: TO-220F2, TM3: TO-251, TN3: TO-252</p> <p>(3) L: Lead Free, G: Halogen Free and Lead Free</p> |
|--|--|



MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$, unless otherwise specified)

| PARAMETER | | SYMBOL | RATINGS | UNIT |
|------------------------------------|------------------------|-----------|------------|------------------|
| Drain-Source Voltage | | V_{DSS} | 500 | V |
| Gate-Source Voltage | | V_{GSS} | ± 30 | V |
| Drain Current | Continuous | I_D | 5 | A |
| | Pulsed (Note 2) | I_{DM} | 20 | A |
| Avalanche Current (Note 2) | | I_{AR} | 4.3 | A |
| Avalanche Energy | Single Pulsed (Note 3) | E_{AS} | 92 | mJ |
| Peak Diode Recovery dv/dt (Note 4) | | dv/dt | 1.7 | V/ns |
| Power Dissipation | TO-220 | P_D | 78 | W |
| | TO-220F/TO-220F1 | | 36 | W |
| | TO-220F2 | | 29 | W |
| | TO-251/TO-252 | | 54 | W |
| Junction Temperature | | T_J | +150 | $^\circ\text{C}$ |
| Storage Temperature | | T_{STG} | -55 ~ +150 | $^\circ\text{C}$ |

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature

3. $L = 10\text{mH}$, $I_{AS} = 4.3\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$

4. $I_{SD} \leq 5.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

■ THERMAL DATA

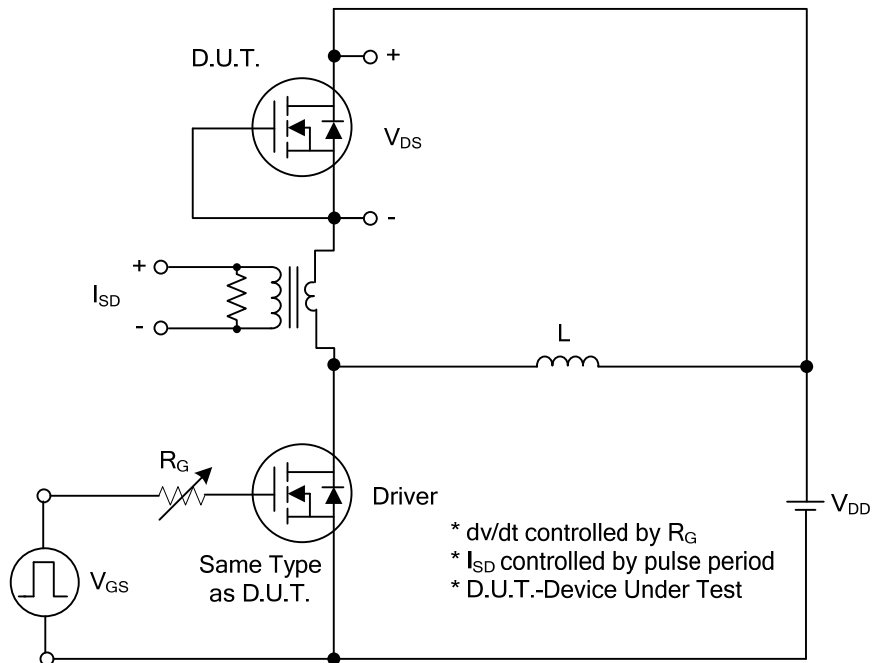
| PARAMETER | PACKAGE | SYMBOL | RATINGS | UNIT |
|---------------------|-------------------|---------------|---------|---------------------------|
| Junction to Ambient | TO-220/TO-220F | θ_{JA} | 62.5 | $^\circ\text{C}/\text{W}$ |
| | TO-220F1/TO-220F2 | | | |
| | TO-251/TO-252 | | | |
| Junction to Case | TO-220 | θ_{JC} | 1.16 | $^\circ\text{C}/\text{W}$ |
| | TO-220F/TO-220F1 | | 4.2 | $^\circ\text{C}/\text{W}$ |
| | TO-220F2 | | 4.18 | $^\circ\text{C}/\text{W}$ |
| | TO-251/TO-252 | | 2.3 | $^\circ\text{C}/\text{W}$ |

■ ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, unless otherwise specified)

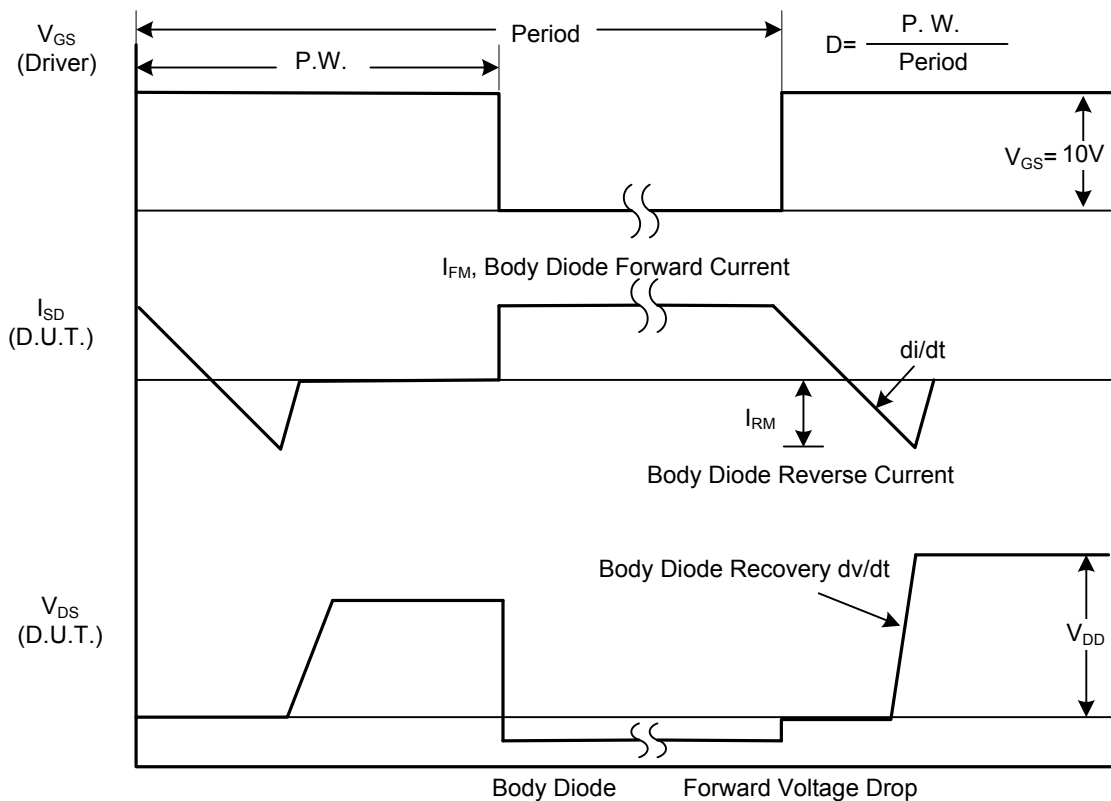
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--|--------------|---|-----|-----|------|---------------|
| OFF CHARACTERISTICS | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$ | 500 | | | V |
| Drain-Source Leakage Current | I_{DSS} | $V_{DS}=500\text{V}$, $V_{GS}=0\text{V}$ | | | 1 | μA |
| Gate- Source Leakage Current | Forward | I_{GSS} | | | 100 | nA |
| | Reverse | | | | -100 | nA |
| ON CHARACTERISTICS | | | | | | |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$ | 2.0 | | 4.0 | V |
| Static Drain-Source On-State Resistance | $R_{DS(ON)}$ | $V_{GS}=10\text{V}$, $I_D=2.5\text{A}$ | | | 1.65 | Ω |
| DYNAMIC PARAMETERS | | | | | | |
| Input Capacitance | C_{ISS} | $V_{GS}=0\text{V}$, $V_{DS}=25\text{V}$, $f=1.0\text{MHz}$ | | 565 | | pF |
| Output Capacitance | C_{OSS} | | | 68 | | pF |
| Reverse Transfer Capacitance | C_{RSS} | | | 5.5 | | pF |
| SWITCHING PARAMETERS | | | | | | |
| Total Gate Charge (Note 1) | Q_G | $V_{DS}=50\text{V}$, $V_{GS}=10\text{V}$, $I_D=1.3\text{A}$ $I_G=100\mu\text{A}$ (Note 1, 2) | | 39 | | nC |
| Gate to Source Charge | Q_{GS} | | | 3.2 | | nC |
| Gate to Drain Charge | Q_{GD} | | | 3.6 | | nC |
| Turn-ON Delay Time (Note 1) | $t_{D(ON)}$ | $V_{DD}=30\text{V}$, $V_{GS}=10\text{V}$, $I_D=0.5\text{A}$, $R_G=25\Omega$ (Note 1, 2) | | 35 | | ns |
| Rise Time | t_R | | | 26 | | ns |
| Turn-OFF Delay Time | $t_{D(OFF)}$ | | | 110 | | ns |
| Fall-Time | t_F | | | 31 | | ns |
| SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS | | | | | | |
| Maximum Body-Diode Continuous Current | I_S | | | | 5 | A |
| Maximum Body-Diode Pulsed Current | I_{SM} | | | | 20 | A |
| Drain-Source Diode Forward Voltage (Note 1) | V_{SD} | $I_S=5.0\text{A}$, $V_{GS}=0\text{V}$ | | | 1.4 | V |
| Body Diode Reverse Recovery Time (Note 1) | t_{rr} | $I_S=5.0\text{A}$, $V_{GS}=0\text{V}$, | | 280 | | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | $di_f/dt=100\text{A}/\mu\text{s}$ | | 1.2 | | μC |

- Notes: 1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
 2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

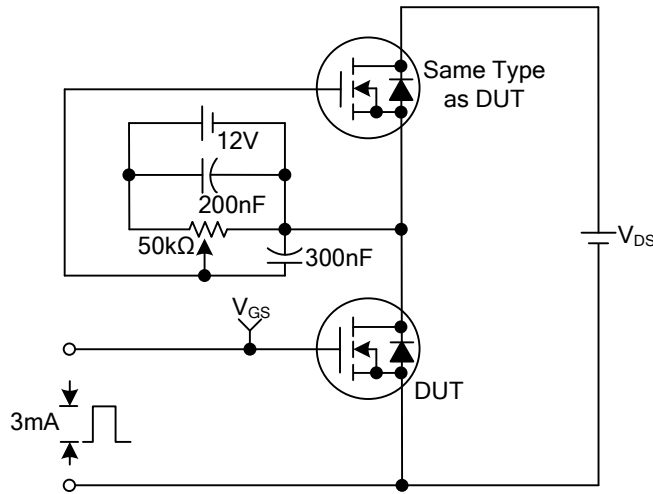


Peak Diode Recovery dv/dt Test Circuit

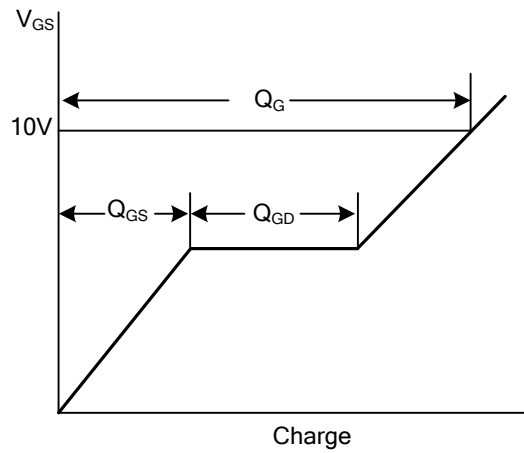


Peak Diode Recovery dv/dt Waveforms

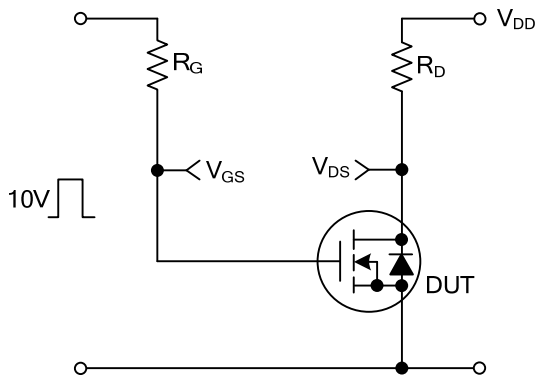
■ TEST CIRCUITS AND WAVEFORMS



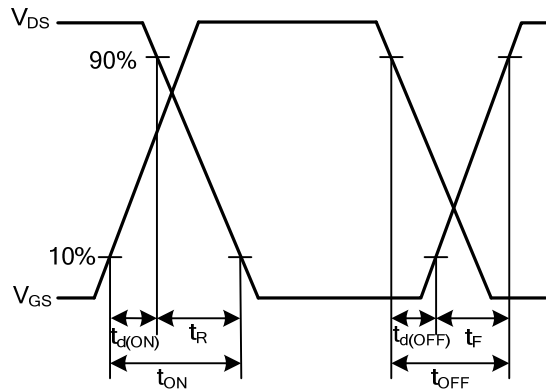
Gate Charge Test Circuit



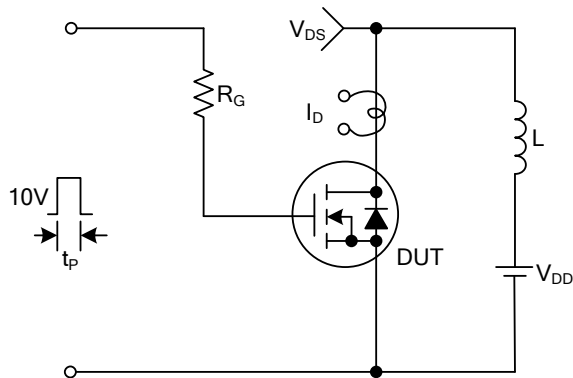
Gate Charge Waveforms



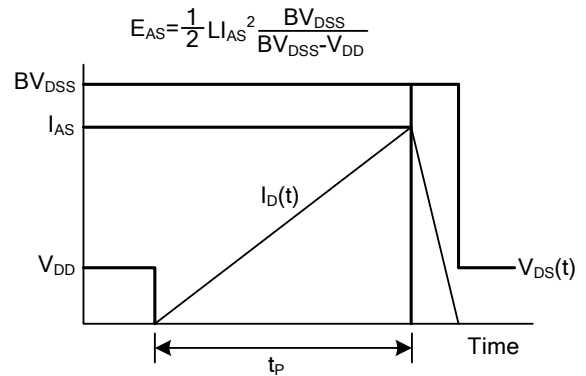
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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